

### **A scalable technique to identify true critical paths in sequential circuits**

**Ubar, Raimund-Johannes; Kostin, Sergei; Jenihhin, Maksim; Raik, Jaan** Proceedings 2017 IEEE 20th International Symposium on Design and Diagnostics of Electronic Circuit & Systems(DDECS) : April 19-21, 2017, Dresden, Germany 2017 / p. 152-157 : ill  
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### **Fast identification of true critical paths in sequential circuits**

**Ubar, Raimund-Johannes; Kostin, Sergei; Jenihhin, Maksim; Raik, Jaan; Jürimägi, Lembit** Microelectronics reliability 2018 / p. 252-261 : ill <https://doi.org/10.1016/j.microrel.2017.11.027> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

### **Gate-level modelling of NBTI-induced delays under process variations**

Copetti, Thiago; Cardoso Medeiros, Guilherme; Bolzani Poehls, Leticia; Vargas, Fabian; **Kostin, Sergei; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes** LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguaçu, Brazil, 6th-9th April 2016 2016 / p. 75-80 : ill <http://dx.doi.org/10.1109/LATW.2016.7483343>

### **Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits**

**Jenihhin, Maksim; Squillero, Giovanni; Tihhomirov, Valentin; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes** Journal of electronic testing : theory and applications (JETTA) 2016 / p. 273-289 : ill <http://dx.doi.org/10.1007/s10836-016-5589-x>

### **On NBTI-induced aging analysis in IEEE 1687 reconfigurable scan networks**

Damljanovic, Aleksa; Squillero, Giovanni; **Gürsoy, Cemil Cem; Jenihhin, Maksim** VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 335-340 : ill <https://doi.org/10.1109/VLSI-SoC.2019.8920313>

### **Rejuvenation of nanoscale logic at NBTI-critical paths using evolutionary TPG**

Palermo, N.; **Tihhomirov, Valentin; Copetti, Thiago; Jenihhin, Maksim; Raik, Jaan; Kostin, Sergei** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill <http://dx.doi.org/10.1109/LATW.2015.7102405>

### **Rejuvenation of NBTI-impacted processors using evolutionary generation of assembler programs**

Pellerey, Francesco; **Jenihhin, Maksim; Squillero, Giovanni; Raik, Jaan; Sonza Reorda, Matteo; Tihhomirov, Valentin; Ubar, Raimund-Johannes** 2016 IEEE 25th Asian Test Symposium : 21-24 November 2016, Hiroshima, Japan 2016 / p. 304-309 : ill <https://doi.org/10.1109/ATS.2016.57>